

N-Channel Enhancement Mode Power MOSFET

● Features

$V_{DS} = 30V$,

$I_D = 68A$

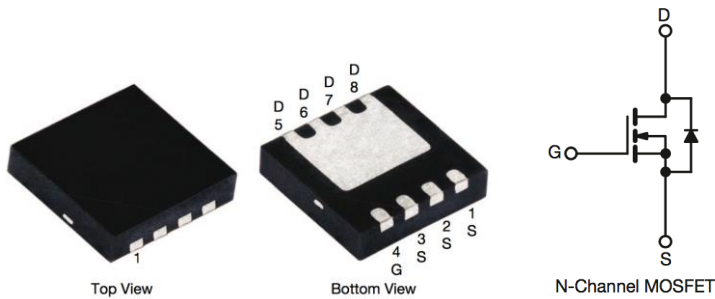
$R_{DS(ON)} @V_{GS} = 10V$, TYP 2.9m Ω

$R_{DS(ON)} @V_{GS} = 4.5V$, TYP 4.8m Ω

● General Description

- load switch
- battery protection applications

● Pin Configurations



TDFN3.3*3.3-8L

● Absolute Maximum Ratings @ $T_A=25^{\circ}C$ unless otherwise noted

Parameter		Symbol	Ratings	Unit
Drain-Source Voltage		V_{DSS}	30	V
Gate-Source Voltage		V_{GSS}	± 20	V
Drain Current (Continuous) *AC	$T_C=25^{\circ}C$	I_D	68	A
	$T_C=70^{\circ}C$		54.5	
Drain Current (Pulse) *B		I_{DM}	150	A
Power Dissipation	$T_C=25^{\circ}C$	P_D	26	W
Operating Temperature/ Storage Temperature		T_J/T_{STG}	-55~150	$^{\circ}C$

● Thermal Resistance Ratings

Parameter		Symbol	Maximum	Unit
Maximum Junction-to-Ambient	$t \leq 10s$	R_{thJA}	34	$^{\circ}C/W$
Maximum Junction-to-Case (Drain)	Steady State	R_{thJC}	4.8	

● Electrical Characteristics @ $T_A=25^{\circ}\text{C}$ unless otherwise noted

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	30	--	--	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 30V, V_{GS} = 0V$	--	--	1	μA
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_{DS} = 250\mu A$	1	1.6	2.5	V
Gate Leakage Current	I_{GSS}	$V_{GS} = \pm 20V, V_{DS} = 0V$	--	--	± 100	nA
Drain-Source On-state Resistance	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 20A$	--	2.9	4	m Ω
	$R_{DS(on)}$	$V_{GS} = 4.5V, I_D = 10A$	--	4.8	6	m Ω
Diode Forward Voltage	V_{SD}	$I_{SD} = 1A, V_{GS} = 0V$	--	0.75	1.2	V
Diode Forward Current *AC	I_S	$T_C = 25^{\circ}\text{C}$	--	--	34.7	A
Switching						
Total Gate Charge	Q_g	$V_{GS} = 10V, V_{DS} = 24V, I_D = 27A$	--	86	--	nC
Gate-Source Charge	Q_{gs}		--	9.2	--	nC
Gate-Drain Charge	Q_{gd}		--	18.6	--	nC
Turn-on Delay Time	$t_{d(on)}$	$V_{DD} = 15V, V_{GS} = 10V,$ $R_L = 1.11\Omega, R_g = 4.7\Omega,$ $I_D = 13.5A$	--	5.7	--	ns
Turn-on Rise Time	t_r		--	14	--	ns
Turn-off Delay Time	$t_{d(off)}$		--	63.7	--	ns
Turn-Off Fall Time	t_f		--	28.4	--	ns
Dynamic						
Input Capacitance	C_{iss}	$V_{DS} = 10V, V_{GS} = 0V, f = 1.0\text{MHz}$	--	3690	--	pF
Output Capacitance	C_{oss}		--	530	--	pF
Reverse Transfer Capacitance	C_{rss}		--	459	--	pF

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}\text{C}$. The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature.

C: The current rating is based on the $\leq 10\text{s}$ junction to ambient thermal resistance rating, package limited 40A

● Typical Performance Characteristics ((T_J = 25 °C, unless otherwise noted))

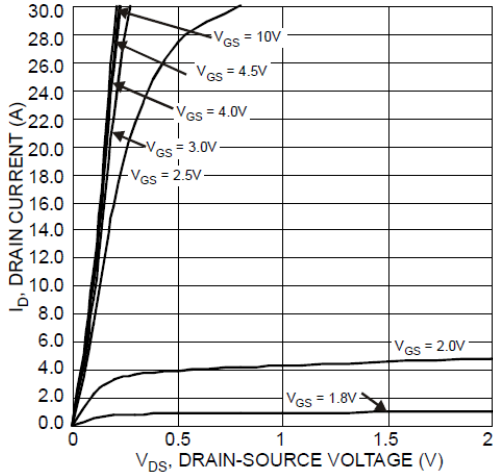


Figure 1 Typical Output Characteristic

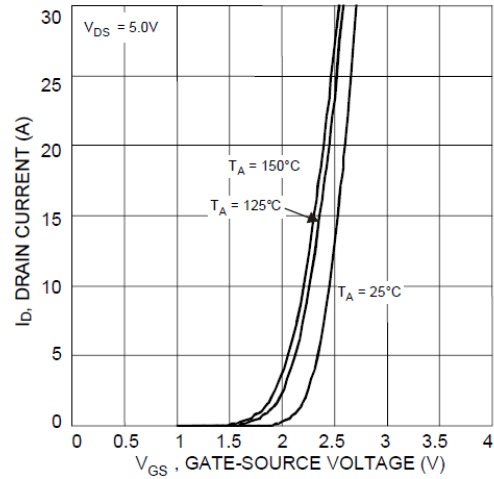


Figure 2 Typical Transfer Characteristics

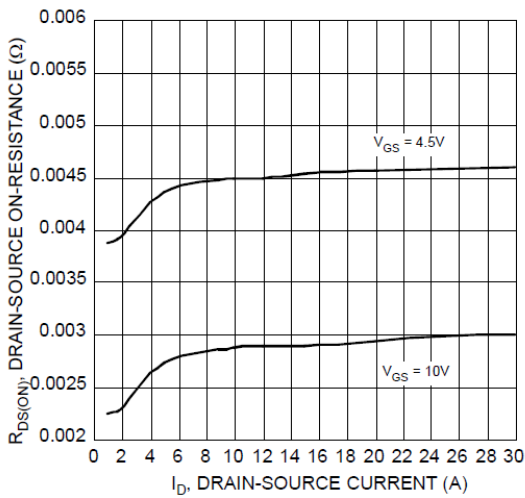


Figure 3 Typical On-Resistance vs. Drain Current and Gate Voltage

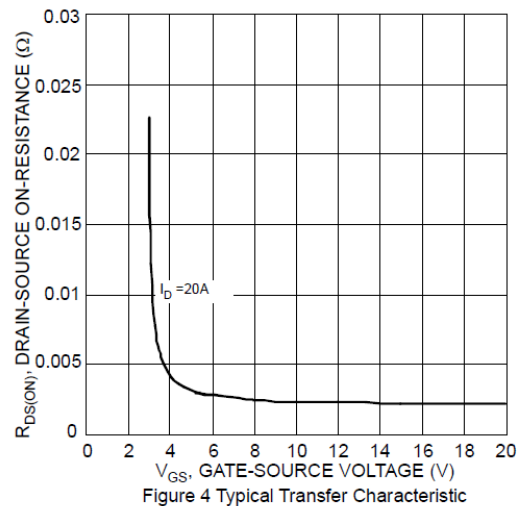


Figure 4 Typical Transfer Characteristic

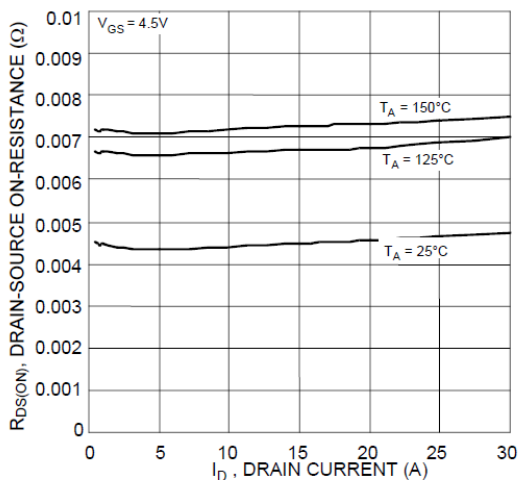


Figure 5 Typical On-Resistance vs. Drain Current and Temperature

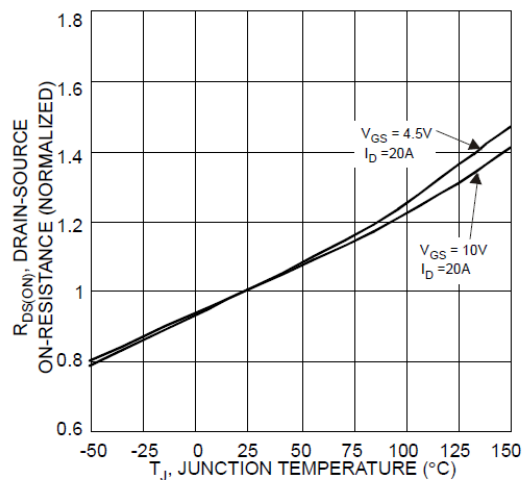


Figure 6 On-Resistance Variation with Temperature

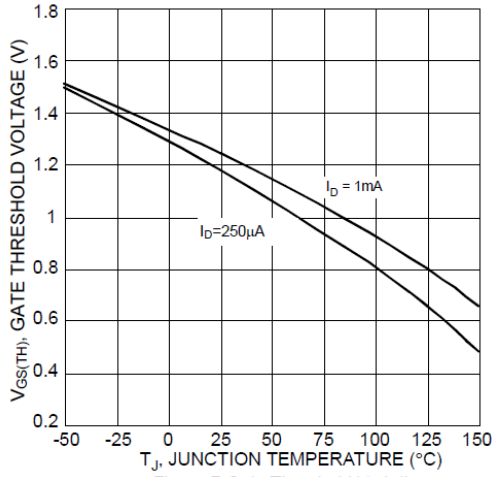


Figure 7 Gate Threshold Variation vs. Junction Temperature

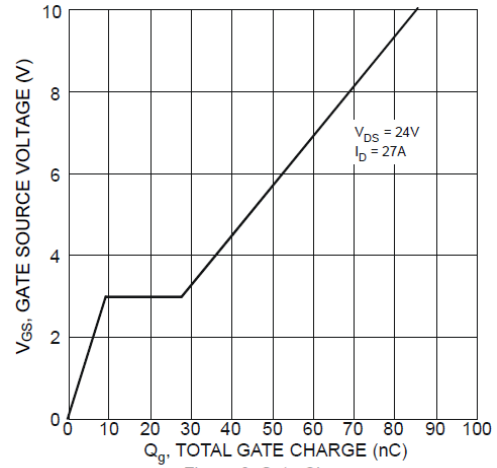


Figure 8 Gate Charge

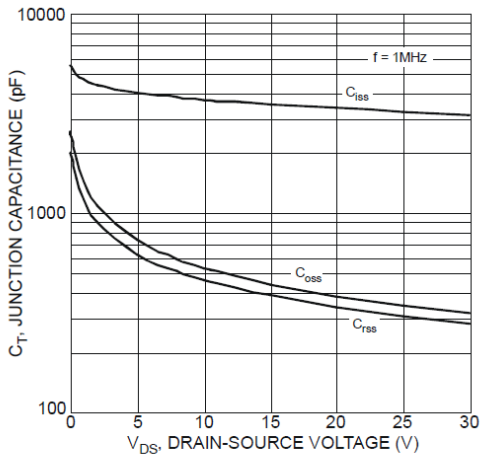


Figure 9 Typical Junction Capacitance

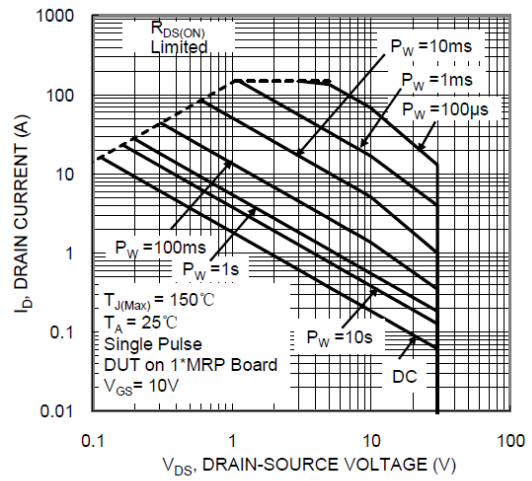


Figure 10. SOA, Safe Operation Area

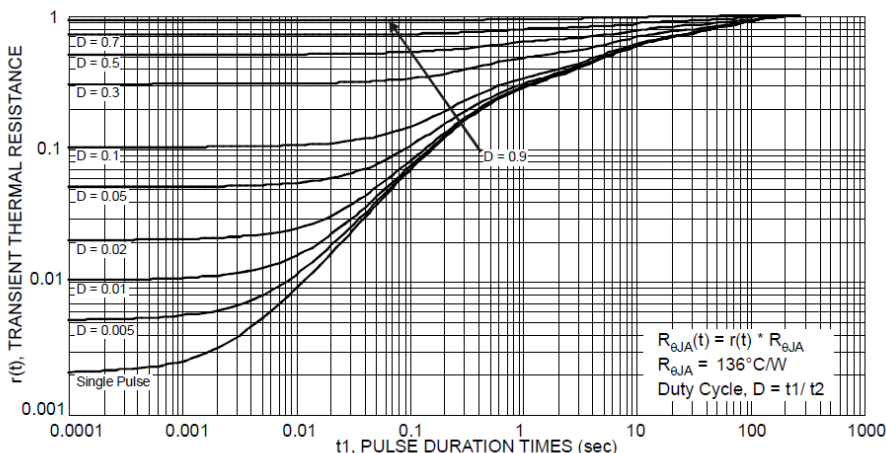
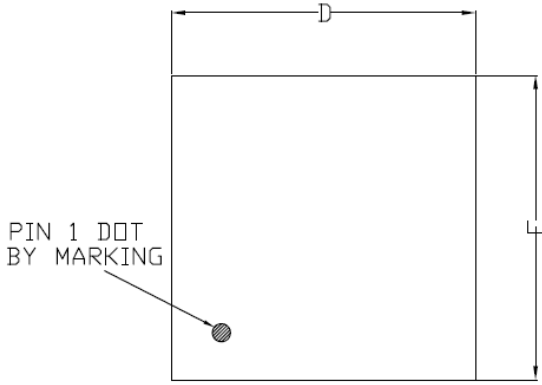


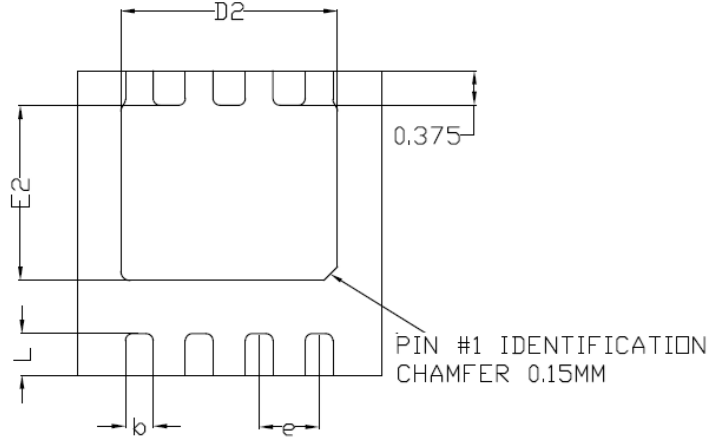
Figure 11 Transient Thermal Resistance

● Package Information

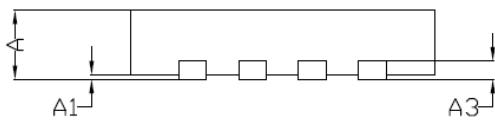
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TOP VIEW



BOTTOM VIEW



SIDE VIEW

COMMON DIMENSIONS(MM)			
PKG. REF.	UT:ULTRA THIN		
	MIN.	NOM.	MAX
A	0.70	0.75	0.80
A1	0.00	-	0.05
A3	0.20 REF.		
D	3.25	3.30	3.35
E	3.25	3.30	3.35
D2	2.30	2.35	2.40
E2	1.85	1.90	1.95
b	0.25	0.30	0.35
L	0.35	0.45	0.55
e	0.65 BSC		